Process Change Notice #1106091

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PCN Date: 9June2011		**Effective Date: 9June2011**
Title: Si57x Datasheet Revision from 1.2 to 1.3		
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PCN Type:

☐ **Assembly**	☐ **Discontinuance**	☐ **Package**	☐ **Test**
☒ **Datasheet**	☐ **Fabrication**	☐ **Product Revision**	
☐ **Packing**	☐ **Labeling**	☐ **Location**	☐ **Other**

Last Order Date: N/A

PCN Details

Description of Change:

Silicon Labs is pleased to announce rev 1.3 for the Si570, Si571 devices. Please refer to Appendix A for a list of document changes and access to this datasheet online.

Reason for Change: To ensure datasheet is consistent with the functionality of the Si57x devices

Impact on Form, Fit, Function, Quality, Reliability: There is no impact on form, fit, function, quality or reliability

Product Identification: Si570, Si571

Last Date of Unchanged Product: N/A

Qualification Samples: N/A

Customer Early Acceptance Sign Off:

Customers may approve early PCN acceptance by completing the information below:

Early Acceptance Date:

Name:

Company:

Email your early Acceptance approval to: katherine.haggar@silabs.com

Qualification Data: N/A

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Appendix A:

Si570/71 datasheet revision 1.2 to v1.3 changes:

- Updated Table 3 on page 6 to include 7 ppm temperature stability and 20 ppm to stability parameters. Also changed aging test condition (frequency drift over life) from 15 years to 20 years.
- Updated 2.5 V/3.3 V and 1.8 V CML output level specification for Table 4 on page 7.
- Added footnotes clarifying max offset frequency test conditions in Table 5 on page 8.
- Updated ESD HBM sensitivity rating and the JEDEC standard in Note 2 on Table 10 on page 12.
- Updated Table 11 on page 13 to include "Moisture Sensitivity Level" and "Contact Pads" rows.
- Added Si570 7 ppm Total Stability Ordering Option to Figure 6 on page 27.
- Updated Figure 7 and Table 15 on page 28 to reflect specific marking information. Previously, Figure 7 was generic.
- Clarified "3.1.2. Reconfiguring the Output Clock for Large Changes in Output Frequency" on page 15 and added new registers 13-18 in "4. Serial Port Registers" on page 18 for the Si570 7 ppm temperature stability / 20 ppm total stability ordering option.
- Added text to "3. Functional Description" on page 14, paragraph 1, to state that the total output jitter complies to and exceeds strict requirements of various high-speed communication systems.

Access to online datasheets:

Si570/71 Datasheet v1.3 can be found here:
http://www.silabs.com/Support%20Documents/TechnicalDocs/si570.pdf

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